# RENESAS

# M62021L/P/FP

System Reset IC with Switch for Memory Backup

REJ03D0784-0200 Rev.2.00 Jun 15, 2007

## Description

The M62021 is a system IC that controls the memory backup function of microcomputer (internal RAM).

The IC outputs reset signals (RES/ $\overline{\text{RES}}$ ) to a microcomputer at power-down and power failure. It also shifts the power supply to RAM from main to backup, outputs a signal ( $\overline{\text{CS}}$ ) that invokes standby mode, and alters RAM to backup circuit mode.

The M62021 contains, in a single chip, power supply monitor and RAM backup functions needed for a microcomputer system, so that the IC makes it possible to construct a system easily and with fewer components compared with a conventional case that uses individual ICs and discrete components.

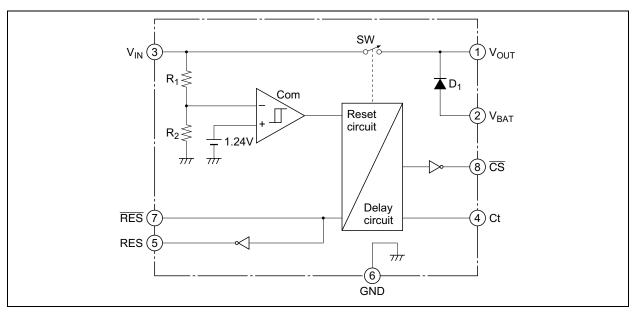
### Features

- Built-in switch for selection between main power supply and backup power supply to RAM.
- Small difference between input and output voltage ( $I_{OUT} = 80$  mA,  $V_{IN} = 5$  V) 0.2 V Typ
- Detection voltage (power supply monitor voltage) 4.40 V  $\pm$  0.2 V
- Chip select signal output  $(\overline{CS})$
- Two channels of reset outputs (RES/RES)
- Power on reset circuit built-in
- Delay time variable by an external capacitance connected to Ct pin
- · Facilitates to form backup function with a few number of components

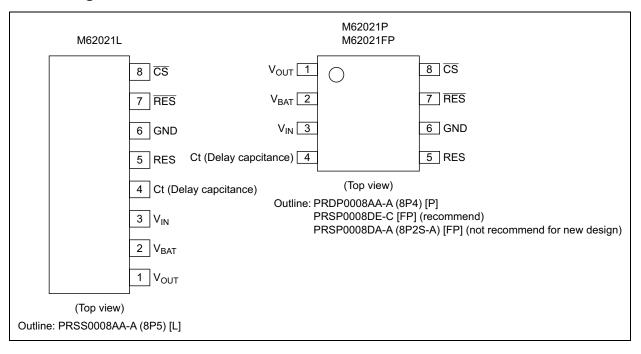
### Application

• Power supply control systems for memory backup of microcomputer system and SRAM boards with built-in backup function that require switching between external power supply and battery.

# **Block Diagram**



### **Pin Arrangement**



# **Absolute Maximum Ratings**

 $(Ta = 25^{\circ}C, unless otherwise noted)$ 

ltem	Symbol	Ratings	Unit	Conditions		
Input voltage	V <sub>IN</sub>	7	V			
Output current	I <sub>OUT</sub>	100	mA			
Power dissipation	Pd	800	mW	8-pin SIP		
		625		8-pin DIP		
		440		8-pin SOP		
Thermal derating	Kθ	8	mW/°C	Ta ≥ 25°C	8-pin SIP	
		6.25			8-pin DIP	
		4.4			8-pin SOP	
Operating temperature	Topr	-20 to +75	°C			
Storage temperature	Tstg	-40 to +125	°C			

# **Electrical Characteristics**

Item	Symbol	Min	Тур	Max	Unit	$(Ta = 25^{\circ}C, unless otherwise noted)$ Test Conditions			
Detection voltage	Vs	4.2	4.4	4.6	V	$V_{IN}$ (at the change from H $\rightarrow$ L)			
0	•			-	-	, <b>,</b> ,			
Hysteresis voltage	ΔVs	50	100	200	mV	$\Delta V_{S} = V_{SH} - V_{SL}$			
Temperature coefficient of detection voltage	V <sub>S</sub> /∆T	—	0.005	—	%/°C				
Circuit current	Icc	—	2.0	4.0	mA	$I_{OUT} = 0mA$	$V_{IN} = 4V$		
			7.5	12.0			$V_{IN} = 5V$		
Difference between input and	VDROP		0.125	0.25	V	$V_{IN} = 5V$	$I_{OUT} = 50 \text{mA}$		
output voltage			0.2	0.4			I <sub>OUT</sub> = 80mA		
Ct output voltage (high level)	V <sub>OH(Ct)</sub>	4.5	5.0	—	V	$V_{IN} = 5V^{*1}$			
Ct output voltage (low level)	V <sub>OL(Ct)</sub>		0.02	0.1	V	$V_{IN} = 4V^{*1}$			
RES output voltage (high level)	V <sub>OH(RES)</sub>	3.5	4.0	_	V	$V_{IN} = 4V^{*1}$			
RES output voltage (low level)	V <sub>OL(RES)</sub>		0.02	—	V	$V_{IN} = 5V$	*1		
			0.05	0.2	1		lsink = 1mA		
RES output voltage (high level)	V <sub>OH(RES)</sub>	4.5	5.0	_	V	$V_{IN} = 5V^{*1}$	•		
RES output voltage (low level)	VOL(RES)		0.02	—	V	$V_{IN} = 4V$	*1		
			0.05	0.2	1		lsink = 1mA		
CS output voltage (high level)	V <sub>OH(CS)</sub>	3.50	3.57	—	V	$V_{IN} = 4V^{*2}$			
		2.40	2.47	—		$V_{IN} = 0V, V_{BAT} =$	3V * <sup>2</sup>		
CS output voltage (low level)	V <sub>OL(CS)</sub>		0.08	_	V	$V_{IN} = 5V$	*1		
			0.1	0.3	1		lsink = 1mA		
Backup diode leakage current	I <sub>R</sub>		_	±0.5	μΑ	$V_{BAT} = 3V$	$V_{IN} = 5V$		
			_	±0.5			$V_{IN} = 0V$		
Backup diode forward direction voltage	V <sub>F</sub>	—	0.54	0.6	V	I <sub>F</sub> = 10μA	·		
Delay time	t <sub>pd</sub>	10	27	55	ms	$V_{IN} = 0V \rightarrow 5V, Ct = 4.7\mu F$			
Response time	t <sub>d</sub>	_	5.0	25.0	μS	V <sub>IN</sub> = 5V→4V			
RES limit voltage of operation	$V_{OPL(\overline{RES})}$		0.65	_	V	*3			

Notes: 1. Regarding conditions to measure V<sub>OH</sub> and V<sub>OL</sub>, voltage values are to be generated by internal resistance only and no external resistor is used.

2. These values are produced inserting an external resistor,  $R_{\overline{CS}} = 1 M\Omega$ , between the  $\overline{CS}$  pin and GND.

3. With no external resistor (10 k $\Omega$  internal resistance only)

## **Test Circuit**

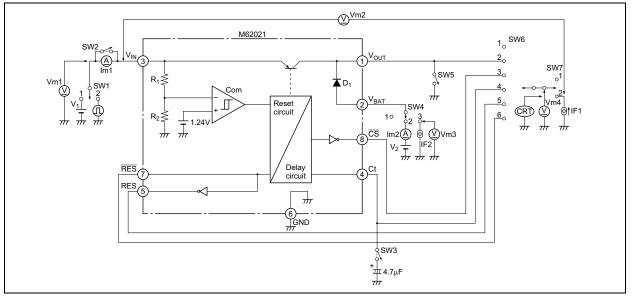


Figure 1 Test Circuit

### **Switch Matrix**

						SW				Measuring			
Item	Symbol	V1	V2	IF1	IF2	1	2	3	4	5	6	7	Instrument
Circuit current	I <sub>cc</sub>	4V 5V	-	_	-	1	ON	OFF	1	OFF	1	1	lm1
Detection voltage (V <sub>IN</sub> negative-going)	V <sub>S</sub> (V <sub>SL</sub> )	Decrease from 5V		_		1	ON	OFF	1	OFF	2 3 4 5 6	1	* <sup>2</sup> Vm4 CRT Vm1
Difference between input and output voltage	V <sub>DROP</sub>	5V	_	-50mA -80mA	_	1	ON	OFF	1	OFF	2	2	Vm2
Ct output voltage (high level) Ct output voltage (low level)	V <sub>OH(Ct)</sub> V <sub>OL(Ct)</sub>	5V 4V	—	_	—	1	ON	OFF	1	OFF	4	1	Vm4
RES output voltage (high level) RES output voltage (low level)	V <sub>OH(RES)</sub> V <sub>OL(RES)</sub>	4V 5V	_	_	-	1	ON	OFF	1	OFF	5	1	Vm4
RES output voltage (high level)	V <sub>OH(RES)</sub>	5V		1mA —		1	ON	OFF	1	OFF	6	2 1	Vm4
RES output voltage (low level)	V <sub>OL(RES)</sub>	4V	_	1mA	_	1	ON	UFF		OFF	0	2	V1114
CS output voltage (high level) *1	V <sub>OH(CS)</sub>	4V 0V		- 1	_	1	ON	OFF	1	OFF	3	1	Vm4
CS output voltage (low level)	V <sub>OL(CS)</sub>	5V	_	1mA								2	
Backup diode leakage current	I <sub>R</sub>	5V 0V	3V	—	_	1	ON	OFF	2	OFF	1	1	lm2
Backup diode forward direction voltage	V <sub>F</sub>	0V	_	_	10µA	1	ON	OFF	3	ON	1	1	Vm3
Delay time CS Response time RES RES	t <sub>pd</sub> t <sub>d</sub>	_	_	_	-	2 * <sup>3</sup>	ON	ON * <sup>4</sup>	1	OFF	2 3 5 6	1	CRT

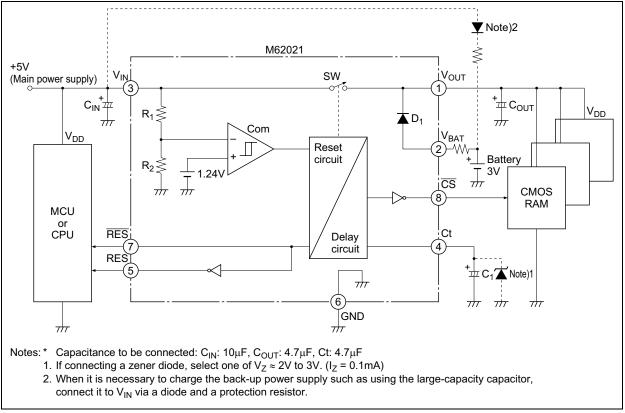
Notes: 1. To measure  $V_{OH(\overline{CS})},$  insert a 1  $M\Omega$  resistor between the  $\overline{CS}$  pin and GND.

- 2. While monitoring each output by Vm4 or CRT, measure the input voltage Vm1 when the output goes from H to L and L to H. Regarding V<sub>SH</sub>, raise V<sub>IN</sub> from 4 V and measure the input voltage Vm1 when the output goes from H to L and L to H.  $\Delta V_S$  is  $V_{SH} V_{SL}$ .
- 3. To measure delay time, change VIN from 0 V to 5 V and compare, with respect to each pin, the positive-going edge observed on a monitor with that of V<sub>IN</sub>. To measure response time, change V<sub>IN</sub> from 5 V to 4 V and compare, with respect to each pin, the negative-going edge observed on a monitor with that of V<sub>IN</sub>.
- 4. Set the switch to OFF when measuring response time.

### **Pin Description**

Pin No.	Pin Name	Symbol	Function	
1	Power supply output	Vout	VIN and VBAT are controlled by means of an internal switch and output through VOUT. The pin is capable of outputting up to 100 mA. Use it as VDD of CMOS RAM and the like.	
2	Backup power supply input	VBAT	Backup power supply is connected to this pin. If a lithium battery is used, insert a resistor in series for safety purposes.	
3	Power supply input	VIN	+5 V input pin. Connect to a logic power supply.	
4	Delay capacitor connection pin	Ct	A delay capacitor is connected to this pin. By connecting a capacitor, it is possible to delay each output.	
5	Positive reset output	RES	Connect to the positive reset input of a microcomputer. The pin is capable of flowing 1 mA sink current.	
6	Ground	GND	Reference for all signals.	
7	Negative reset output	RES	Connect to the negative reset input of a microcomputer. The pin is capable of flowing 1 mA sink current.	
8	Chip select output	CS	Connect to the chip select of RAM. The CS output is at low level in normal state thereby letting RAM be active. Under failure or backup condition, the CS output is set to high level, then RAM enters standby state disabling read/write function. The pin is capable of flowing a 1 mA sink current.	

## **Application Example**



#### Figure 2 Application Example

### Configuration

#### **Power Supply Detection**

The internal reference voltage Vref is compare by means of a comparator with resistor-divided voltage  $V_R$  (resistor-divided voltage produced by  $R_1$  and  $R_2$  from  $V_{IN}$ ).

If the input voltage is 5 V,  $V_R$  is set to 1.24 V or higher, so the comparator output is at low level and the Ct output ( $Q_1$  collector output) is set to high level. If the input voltage drops to below 4.4 V in an abnormal condition,  $V_R$  becomes below 1.24 V, so the comparator output goes from low to high level and the Ct output, from high to low. The input voltage at this point is called  $V_{SL}$ . Next, when the input voltage, restored from abnormal state, has a rise, the comparator output goes from high to low level and the Ct output, from low to high.

The comparator used for detection has 100 mV hysteresis ( $\Delta V_s$ ), so that malfunctioning is prevented in case that the input voltage slowly drops or  $V_R$  nearly equals Vref.

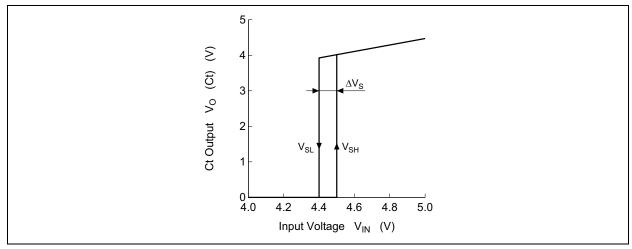


Figure 3

#### **Delay Circuit**

Connecting an external capacitor to the Ct pin lets RES,  $\overline{\text{RES}}$ ,  $\overline{\text{CS}}$ , and  $V_{\text{OUT}}$  be delayed due to RC transient phenomenon (electric charge).

Delay time is determined as follows.

Delay time  $(t_{pd}) = C_1 \times (R_3 + R_4) \times 1n \frac{[V_{OH}(Ct) - V_{OL}(Ct)]}{[V_{OH}(Ct) - INV1(V_{TH})]}$ =  $C_1 \times 22k\Omega \times 0.2614$  $\approx 5.75 \times 10^3 \times C_1$ \* C is an external capacitance.

Taking into consideration the time taken by the oscillator of microcomputer to be stable, connect a 4.7  $\mu$ F capacitor to the Ct pin. (As the response time of detection can be slowed due to internal structure depending in the rising rate of power supply, avoid connecting a too large capacitance.)

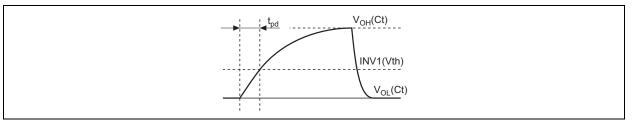


Figure 4 Delayed Output Waveforms of Ct

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#### Schmitt Trigger Circuit

Since waveforms show a gentle rise due to the RC delay circuit, INV1, INV2, R5, and R6 constitute a Schmitt trigger circuit to produce hysteresis so as to prevent each output from chattering.

### **Internal Circuit**

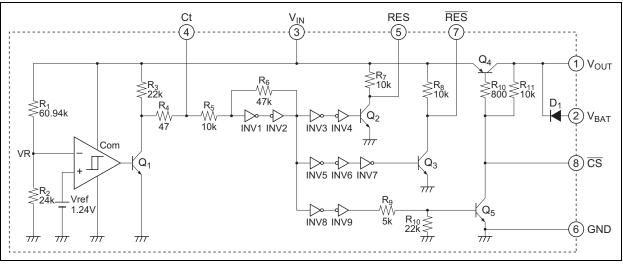


Figure 5 Internal Circuit

# **Timing Chart**

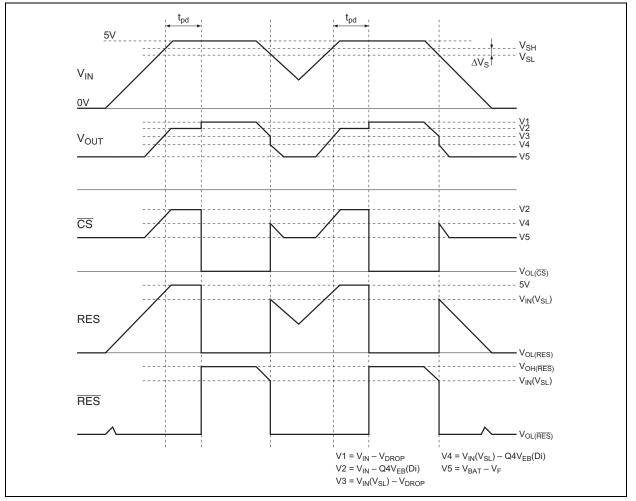
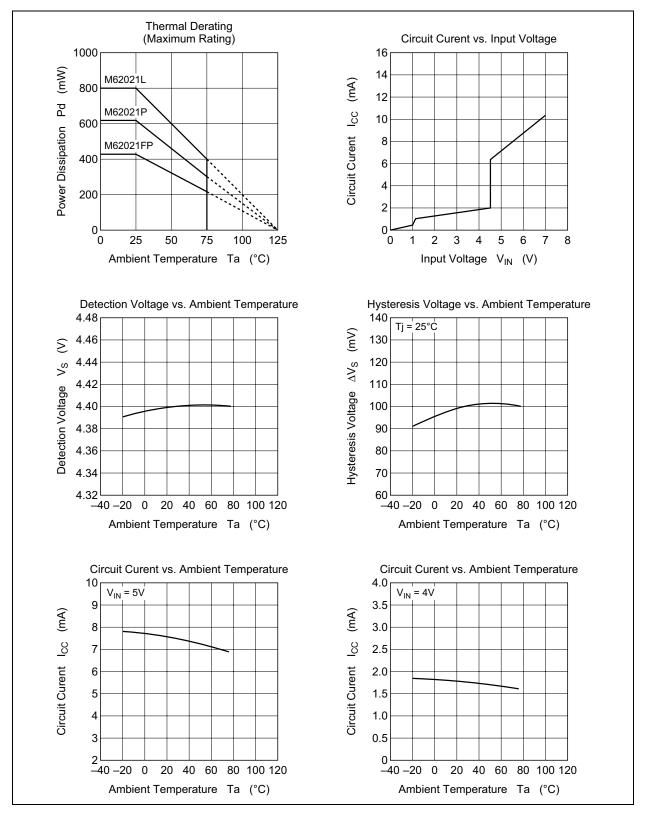


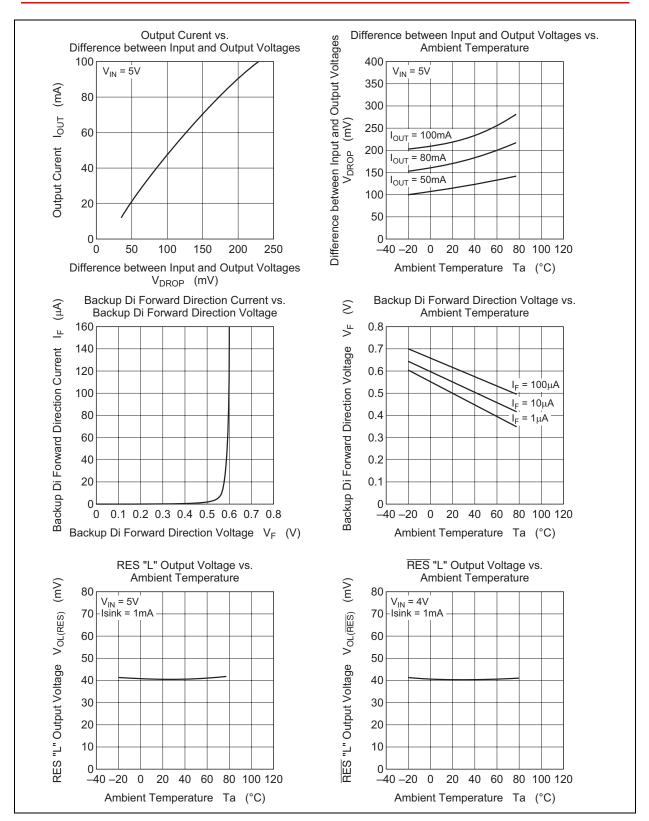
Figure 6 Timing Chart

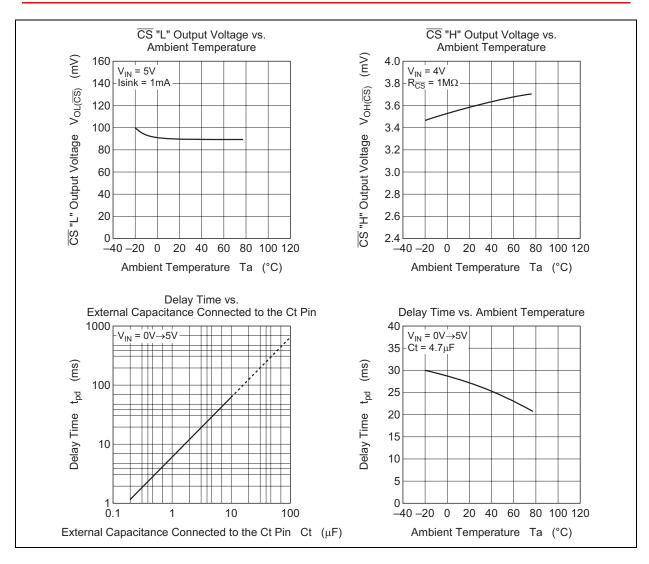
Input Voltage	In Normal Operation	In Failure (Instantaneous Drop)	Restoration from Failure (Instantaneous Drop)	In Backup State
Output Pin	Input voltage: 5V	Input voltage: $5V \rightarrow 4V$ Each output varies if the input voltage drops to $V_{SL}$ or under	Input voltage: $4V \rightarrow 5V$ If the input voltage goes higher than VSL by 100mV, each output varies after delay produced by the delay circuit	Input voltage: 0V Backup voltage: 3V
V <sub>OUT</sub>	With Q4 set to ON, a voltage $(V_{IN} - V_{DROP})$ is output	Q4 is turned OFF. A voltage $(V_{IN} - Q4V_{EB}(Di))$ is output by the diode between E and B of Q4.	Q4 is turned ON after delay and a voltage ( $V_{IN} - V_{DROP}$ ) is output.	$V_{BAT} - V_F$
RES	The output level is $V_{OL}$ (RES) with a logic low	As the state shifts from a logic low to logic high, the output level becomes approximately equal to the input voltage.	A logic high is maintained, and than shifts to a logic high.	_
RES	The output level is $V_{OH}$ (RES) with a logic low	As the state shifts from a logic high to logic low, the output level becomes $V_{OL}$ (RES).	A logic low is held, and than shifts to a logic high.	—
CS	The output level is $V_{OL}$ ( $\overline{CS}$ ) with a logic low	As the state shifts from a logic low to logic high, the output level becomes the voltage $V_{IN} - Q4V_{EB}(Di)$ .	A logic high is maintained, and than shifts to a logic high.	The output is a logic high and the output level is $V_{\text{BAT}}-V_{\text{F}}$

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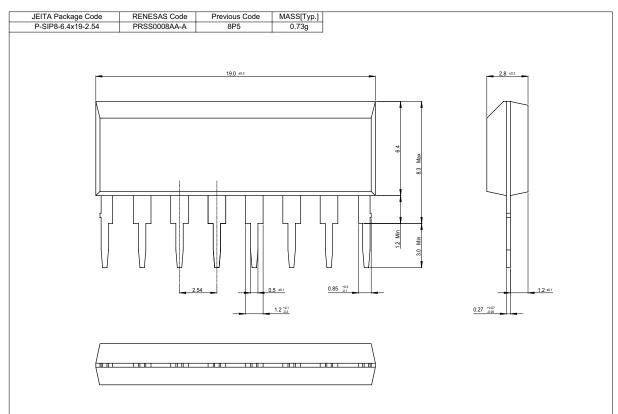
### **Typical Characteristics**

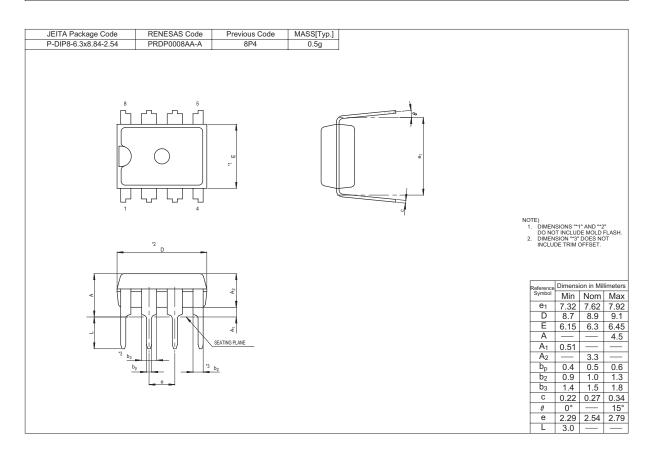






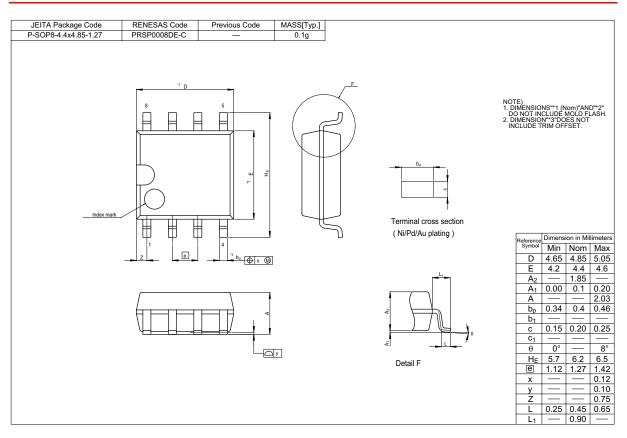
### **Package Dimensions**

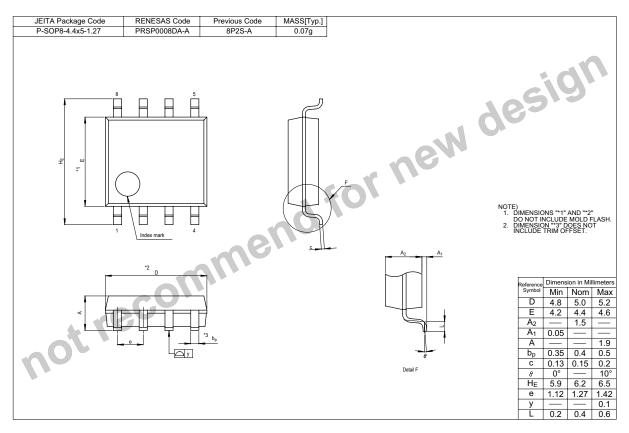




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